FORM PTO-1449 (Modified) U.S. Department of Commerce Patent and Trademark Office Serial No.: 09/841,800 Attorney Docket No.: SSI-02001 FOR PATION DISCLOSURE STATEMENT BY APPLICANT (Use Several Sheets If Necessary) TOTAL Applicant: Maximilian Biberger et al. Group Art Unit: えるるち Filing Date: April 24, 2001 CFR § 1.98(b)) 7NN 5 8 5000 U.S. PATENT DOCUMENTS Exerciner In reds Serial / Patent Subclass Filing Date Issue Date Applicant / Patentee Class Number RADEM 12/29/50 23 312 11/11/52 C. R. Stewart 2,617,719 2 12/17/73 1 me 06/17/75 Bolon 156 AB 3,890,176 03/02/72 9 Bardoncelli et al. 423 にかれも AC 3,900,551 08/19/75 03/01/76 06/14/77 Rand 134 11 4,029,517 AD 18C 02/17/77 Zucchini 68 05/30/78 AE 4,091,643 08/04/75 643 156 AF 4,341,592 07/27/82 Shortes et al. 134 105 11/09/82 AC 10/02/84 Blaudszun 4,474,199 08/15/83 64T 10/09/84 Blander et al. 204 4,475,993 AH 68 18C 11/17/83 4,601,181 07/22/86 Privat ΑI 156 345 11/27/85 09/15/87 Hazano et al. ΑJ 4,693,777 156 646 05/12/87 06/07/88 Blackwood et al. ΑK 4,749,440 422 292 04/17/86 4,788,043 11/29/88 Kagiyama et al. AL 180.1 11/12/87 06/13/89 Rahn 228 AM 4,838,476 Fowler et al. 134 108 07/22/83 4,865,061 09/12/89 AN ΑO 4,879,004 11/07/89 Oesch et al. 203 89 05/04/88 05/26/89 Stark et al. 414 217 ΑP 4,917,556 04/17/90 08/07/89 437 225 05/08/90 Gluck et al. AQ 4,923,828 123 07/28/88 AR 4,924,892 05/15/90 Kiba et al. 134 02/28/89 646 AS 4,944,837 07/31/90 Nishikawa et al. 156 11/27/85 10/02/90 Ishijima et al. 134 31 AT 4,960,140 10/24/89 01/08/91 Gessner 134 25.4 ΑU 4,983,223 134 38 07/21/88 ΑV Weil 04/30/91 5,011,542 12/07/88 134 1 AW 5,013,366 05/07/91 Jackson et al. 748 04/03/89 210 ΑX 5,068,040 11/26/91 Jackson 12 08/09/88 34 04/21/92 Kurokawa et al. AY 5,105,556 01/04/91 98.1 09/01/92 Basso et al. 134 ΑZ 5,143,103 07/25/90 BA 10/27/92 Fulton et al. 252 309 5,158,704 252 60 07/19/91 5,174,917 12/29/92 Monzyk BB 01/29/91 156 656 BC Cathey, Jr. 5,185,058 02/09/93 437 229 04/24/91 02/09/93 Morita et al. BD 5,185,296 29 25.01 04/15/91 BE 5,186,718 02/16/93 Tepman et al 56R 06/24/91 134 BF 03/16/93 Tanaka et al. 5,193,560 11/30/89 BG 5,213,619 05/25/93 Jackson et al. 134 134 01/22/91 ВН 5,215,592 06/01/93 Jackson ΒI 07/06/93 Wai 423 2 10/25/91 5,225,173 210 748 01/28/91 BJ 5,236,602 08/17/93 Jackson 7-25-02 lverkus Date Considered: Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form **EXAMINER:** with next communication to applicant.

FORM PTO-1449 (Modified)

U.S. Department of Commerce Patent and Trademark Office

Attorney Docket No.: SSI-02001

Serial No.: 09/841,800

INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use Several Sheets If Necessary)

NT Applicant: Maximilian Biberger et al.

Filing Date: April 24, 2001

Group Art Unit: 2825

(37 CFR § 1.98	3(b))			Filing Date: April 24,	2001	Group Art Unit	
01	PE			U.S. PATENT DOCUMENTS			
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Examiner:	C. Sweishast Date Considered: 7-25-09						

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Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

U.S. Department of Commerce Patent and Trademark Office FORM PTO-1449 (Modified) Attorney Docket No.: SSI-02001 Serial No.: 09/841,800 OIP INFORMATION DISCOSURE STATEMENT BY APPLICANT (Use Several Sheets If Necessary) Applicant: Maximilian Biberger et al. Group Art Unit: 2825 Filing Date: April 24, 2001 (37 CFR § .98(**h) 2 8** U.S. PATENT DOCUMENTS TRADEM al / Patent Examiner Applicant / Patentee Subclass Filing Date Class Issue Date Initials Number 09/01/93 694 ML 428 08/20/96 Gimzewski et al. CU 5,547,774 12/17/92 480 CV 08/27/96 DeCrosta et al. 528 5,550,211 510 175 01/09/95 CW 12/03/96 Hayashida et al. 5,580,846 06/07/95 216 12/31/96 Lin et al. CX 5,589,082 05/18/95 252 351 12/31/96 DeSimone et al. CY 5,589,105 369 112 01/20/95 CZ 5,629,918 05/13/97 Ho et al. 04/24/95 156 344 05/27/97 Ohno et al. DA 5,632,847 175 07/19/95 DB 5,635,463 06/03/97 Muraoka 510 134 2 06/27/94 06/10/97 Schulz DC 5,637,151 Beckman et al. 546 26.2 04/01/94 06/24/97 DD 5,641,887 12/21/94 08/12/97 Olesen et al. 134 1 DE 5,656,097 325 02/03/97 09/09/97 430 DF 5,665,527 Allen et al. 12/19/95 1.3 10/21/97 Gonzales et al. 134 DG 5,679,169 03/06/96 DH 5,679,171 10/21/97 Saga et al. 134 3 03/06/95 510 286 DΙ 5,683,977 11/04/97 Jureller et al. 89 02/17/97 DeSimone 526 DJ 5,688,879 11/18/97 02/14/96 Biebl 216 2 DK 5,700,379 12/23/97 61 03/21/96 521 Hedrick et al. DL 5,726,211 03/10/98 06/02/94 638 210 DM 5,730,874 03/24/98 Wai et al. 09/18/95 04/14/98 DeSimone 526 89 DN 5,739,223 11/03/95 07/21/98 DeSimone et al. 210 634 DO 5,783,082 417 46 10/30/96 James et al. DP 5,797,719 08/25/98 09/09/96 08/25/98 528 483 Sawan et al. DQ 5,798,438 10/16/97 521 64 DR 5,804,607 09/08/98 Hedrick et al. 11/01/96 634 210 DS 5,866,005 02/02/99 DeSimone et al. 2 07/23/97 02/09/99 Douglas et al. 134 DT 5,868,856 07/31/97 02/09/99 134 26 DU 5,868,862 Douglas et al. 04/01/97 546 336 D۷ 02/16/99 Beckman et al. 5,872,257 134 19 06/24/97 DW 5,873,948 02/23/99 Kim 68 5 09/09/96 Sauer et al. DX 03/16/99 5,881,577 417 46 08/25/98 03/30/99 Fitzgerald et al. DY 5,888,050 430 395 07/03/97 DΖ 5,900,354 05/04/99 Batchelder 134 2 10/16/96 06/01/99 McCullough et al. EΑ 5,908,510 06/14/96 EB Yager et al. 210 634 5,932,100 08/03/99 05/02/97 EC 5,944,996 08/31/99 DeSimone et al. 210 634

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Date Considered:

7-25-02

FORM PTO-1449 (Modified) U.S. Department of Commerce Patent and Trademark Office Attorney Docket No.: SSI-02001 Serial No.: 09/841,800 INFORM DION DISCLUSURE STATEMENT BY APPLICANT (Use Second Sheets If Necessary) Applicant: Maximilian Biberger et al. Group Art Unit: 2825 Filing Date: April 24, 2001 (37 CFR § 1.9 JUN Z B 2001 U.S. PATENT DOCUMENTS Serial Atent Examiner Initials Subclass Applicant / Patentee Class Filing Date Issue Date מוציים 210 634 01/21/98 ED 5,965,025 10/12/99 Wai et al. 2 11/30/98 11/02/99 McCullough et al. 134 EE 5,976,264 11/09/99 134 34 12/30/93 EF 5,980,648 Adler 438 689 07/17/98 01/25/00 EG 6,017,820 Ting et al. 12/09/96 134 ЕН 6,024,801 02/15/00 Wallace et al. 1 05/30/97 ΕI 6,114,044 09/05/00 Houston et al. 428 447 05/05/97 EJ 6,149,828 11/21/00 Vaartstra 216 57 08/28/98 ΕK 6,242,165 B1 06/05/01 Vaartstra 430 329 FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS Translation Document Number Country / Patent Office Class Subclass **Publication Date** Yes No X EP 0 836 895 A2 04/22/98 **EPO** B08B 7/00 EL X **EPO B08B** 5/00 EM EP 0 726 099 A2 08/14/96 B08B 7/00 Х **EPO** EN EP 0 587 168 A1 03/16/94 X EPO B01D 11/02 12/08/93 EO EP 0 572 913 A1 Clid X 3/20 **EPO** EΡ EP 0 536 752 A2 4/14/93 Х 21/56 H01L EQ JP 2-304941 12/18/90 Japan X 09/28/88 **EPO** C22B 3/00 ER EP 0 283 740 A2 C22B 3/00 Х ES EP 0 302 345 A2 02/08/89 **EPO** C22B 3/00 Х 05/30/90 **EPO** ET EP 0 370 233 A1 EU 10/10/90 EPO C23G 5/00 Х EP 0 391 035 H01L 021/027 02/13/96 EV JP 727711 Japan B01D 011/04 EW JP 1045131 02/17/89 Japan Х JP 2-148841 06/07/90 H01L 21/306 EX Japan 06/02/95 H01L 021/027 EY JP 7142333 Japan H01L 021/027 EZ JP 8222508 08/30/96 Japan FA JP 60-192333 09/30/85 H01L 21/30 Japan H01L 21/30 X FB JP 62-125619 06/06/87 Japan B08B 5/00 Х WO 99/49998 10/07/99 **WIPO** FC ime Х FD WO 90/06189 06/14/90 **WIPO B08B** 7/00 3/00 Х FE WO 90/13675 11/15/90 **WIPO** C22B OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication) J.B. Rubin et al. "A Comparison of Chilled DI Water/Ozone and Co2-Based Supercritical Fluids as Replacements for Photoresist-Stripping Solvents" 1998, pp. 308-314, IEEE/CPMT Int'l Electronics Manufacturing Technology Symposium. FF FG "Los Almos National Laboratory," Solid State Technology, pp. S10 & S14, October 1998. FH "Supercritical Carbon Dioxide Resist Remover, SCORR, the Path to Least Photoresistance," Los Almos National Laboratory, 1998 Guan, Z. et al., "Fluorocarbon-Based Heterophase Polymeric Materials. 1. Block Copolymer Surfactants for Carbon Dioxide Applications," Macromolecules, Vol. 27, 1994, pp 5527-5532. FI 7-25-03 Examiner: weskart Date Considered: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form **EXAMINER:**

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U.S. Department of Commerce Attorney Docket No.: SSI-02001 Serial No.: 09/841,800 FORM PTO-1449 Patent and Trademark Office (Modified) INFORMADON DISCLOSURE STATEMENT BY APPLICANT (Use See and Sheets If Necessary) Applicant: Maximilian Biberger et al. Group Art Unit: 2825 Filing Date: April 24, 2001 (37 CFR § 1.98(b)) JNN 5 R 2001 THER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication) International Journal of Environmentally Conscious Design & Manufacturing, Vol. 2, No. 1, 1993, p. 83. FRADEMAN and Smith "Supercritical Fluids", Journal of the American Ceramic Society, Vol. 72, No. 6, pp. 872-874. Ziger, D.H. et al., "Compressed Fluid Technology: Application to RIE Developed Resists," AIChE Journal, Vol. 33, No. 10, October 1987, pp 1585-1591. ma FL Kirk-Othmer, "Alcohol Fuels to Toxicology," Encyclopedia of Chemical Terminology, 3rd ed., Supplement Volume, 1984, pp. 872-893. 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FORM PTO-1 (Modified)	44° \ F	E	O.S. Department of Commerce Patent and Trademark Office	Attorney Docket No.: SSI-02001	Serial No.: 09/841,860			
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Attorney Docket No.: SSI-02001

Applicant: Maximilian B. Biberger et al.

Serial No.: 09/841,800

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Filing Date: April 24, 2001

Group Art Unit: 2812 2825

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ORM PTO-1449 (Modified) INFORMATION DISCLOSTIFE STATEMENT BY APPLICANT (Use Several sheets if Necessary)

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Attorney Docket No.: SSI-02001

Serial No.: 09/841,800

'Applicant: Maximilian B. Biberger et al.

Group Art Unit: 2812 2825

Filing Date: April 24, 2001 (37 CFR § 1.98(b) FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS Translation Document Number Subclass **Publication Date** Country / Patent Office Class Yes No Х 08/23/90 D 06 L 1/00 BJ DE 39 04 514 C2 Germany \mathbf{X} D 06 P 1/90 09/13/90 BK DE 39 06 724 C2 Germany X 09/06/90 D 06 L 3/00 BL DE 39 06 735 C2 Germany D 06 M 11/59 X BM DE 39 06 737 A1 09/13/90 Germany X 1/00 D 06 L BN DE 40 04 111 C2 08/23/90 Germany X 06/29/95 D 06 P 1/16 BQ DE 43 44 021 A1 Germany X 03/02/95 D 06 L 5/04 DE 44 29 470 A1 Germany BP X D06L 1/02 12/16/92 EP BQ EP 0 518 653 B1 CIID 7/50 Х BR EP 0 620 270 A3 10/19/94 EP 43/00 X EP D06F BS EP 0 679 753 B1 11/02/95 \mathbf{X} EP D06G 1/00 BT EP 0 711 864 B1 05/15/96 D06B 5/16 Х BU WO 93/14255 07/22/93 PCT X PCT D06M 11/76 ΒV WO 93/14259 07/22/93 X C08F 14/18 WO 93/20116 10/14/93 **PCT** BW 1/00 Х WO 96/27704 09/12/96 **PCT** D06L BXBY ΒZ CA CB CC CD CE N CF CG , 7 CH CI õ CJ CK CL CM CN CO CP 7-25-00

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